

BFP540ESD

Low Noise Silicon Bipolar RF Transistor

- For ESD protected high gain low noise amplifier
- High ESD robustness typical value 1000 V (HBM)
- Outstanding G_{ms} = 21.5 dB @ 1.8 GHz Minimum noise figure NF_{min} = 0.9 dB @ 1.8 GHz
- Pb-free (RoHS compliant) and halogen-free package with visible leads
- Qualification report according to AEC-Q101 available



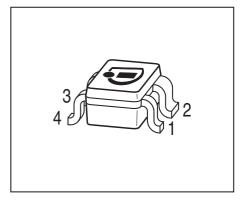
ESD (Electrostatic discharge) sensitive device, observe handling precaution!

Туре	Marking	Pin Configuration					Package	
BFP540ESD	AUs	1=B	2=E	3=C	4=E	-	-	SOT343

Maximum Ratings at T_A = 25 °C, unless otherwise specified

Parameter	Symbol	Value	Unit	
Collector-emitter voltage	V _{CEO}		V	
<i>T</i> _A = 25 °C		4.5		
<i>T</i> _A = -55 °C		4		
Collector-emitter voltage	V _{CES}	10		
Collector-base voltage	V _{CBO}	10		
Emitter-base voltage	V _{EBO}	1		
Collector current	I _C	80	mA	
Base current	I _B	8		
Total power dissipation ¹⁾	P _{tot}	250	mW	
<i>T</i> _S ≤ 77°C				
Junction temperature	TJ	150	°C	
Ambient temperature	T _A	-65 150		
Storage temperature	T _{Stq}	-65 150		

 ${}^{1}T_{S}$ is measured on the emitter lead at the soldering point to the pcb





Thermal Resistance

Parameter	Symbol	Value	Unit
Junction - soldering point ¹⁾	R _{thJS}	290	K/W

Electrical Characteristics at T_A = 25 °C, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	1
DC Characteristics					·
Collector-emitter breakdown voltage	V _{(BR)CEO}	4.5	5	-	V
<i>I</i> _C = 1 mA, <i>I</i> _B = 0					
Collector-emitter cutoff current	I _{CES}	-	-	10	μA
$V_{\rm CE}$ = 10 V, $V_{\rm BE}$ = 0					
Collector-base cutoff current	I _{CBO}	-	-	100	nA
$V_{\rm CB} = 5 \text{ V}, I_{\rm E} = 0$					
Emitter-base cutoff current	I _{EBO}	-	-	10	μA
$V_{\rm EB}$ = 0.5 V, $I_{\rm C}$ = 0					
DC current gain	h _{FE}	50	110	170	-
$I_{\rm C}$ = 20 mA, $V_{\rm CE}$ = 3.5 V, pulse measured					

¹For the definition of R_{thJS} please refer to Application Note AN077 (Thermal Resistance Calculation)



Parameter	Symbol	Values			Unit
		min.	typ.	max.	
AC Characteristics (verified by random sampling	g)	1			T
Transition frequency	f _T	21	30	-	GHz
$I_{\rm C}$ = 50 mA, $V_{\rm CE}$ = 4 V, f = 1 GHz					
Collector-base capacitance	C _{cb}	-	0.14	0.24	pF
$V_{\rm CB} = 2 \text{V}, f = 1 \text{MHz}, V_{\rm BE} = 0 ,$					
emitter grounded					
Collector emitter capacitance	C _{ce}	-	0.41	-	
$V_{CE} = 2 V, f = 1 MHz, V_{BE} = 0$,					
base grounded					
Emitter-base capacitance	C _{eb}	-	0.59	-	
$V_{\rm EB}$ = 0.5 V, f = 1 MHz, $V_{\rm CB}$ = 0 ,					
collector grounded					
Minimum noise figure	NF _{min}				dB
$I_{\rm C}$ = 5 mA, $V_{\rm CE}$ = 2 V, f = 1.8 GHz, $Z_{\rm S}$ = $Z_{\rm Sopt}$		-	0.9	1.4	
$I_{\rm C}$ = 5 mA, $V_{\rm CE}$ = 2 V, f = 3 GHz, $Z_{\rm S}$ = $Z_{\rm Sopt}$		-	1.3	-	
Power gain, maximum stable ¹⁾	G _{ms}	-	21.5	-	dB
$I_{\rm C}$ = 20 mA, $V_{\rm CE}$ = 2 V, $Z_{\rm S}$ = $Z_{\rm Sopt}$,					
$Z_{\rm L} = Z_{\rm Lopt}$, $f = 1.8 \rm GHz$					
Power gain, maximum available ¹⁾	G _{ma}	-	16	-	dB
$I_{\rm C}$ = 20 mA, $V_{\rm CE}$ = 2 V, $Z_{\rm S}$ = $Z_{\rm Sopt}$,					
$Z_{\rm L} = Z_{\rm Lopt}, f = 3 \rm GHz$					
Transducer gain	S _{21e} ²				dB
$I_{\rm C}$ = 20 mA, $V_{\rm CE}$ = 2 V, $Z_{\rm S}$ = $Z_{\rm L}$ = 50 Ω , f = 1.8GHz		16	18.5	-	
$I_{\rm C}$ = 20 mA, $V_{\rm CE}$ = 2 V, $Z_{\rm S}$ = $Z_{\rm L}$ = 50 Ω , f = 3GHz		-	14	-	
Third order intercept point at output ²⁾	IP3	-	24.5	-	dBm
V_{CE} = 2 V, I_{C} = 20 mA, Z_{S} = Z_{L} = 50 Ω , f = 1.8GHz					
1dB compression point at output	P _{-1dB}	-	11	-]
$I_{\rm C}$ = 20 mA, $V_{\rm CE}$ = 2 V, $Z_{\rm S}$ = $Z_{\rm L}$ = 50 Ω , f = 1.8GHz					

Electrical Characteristics at T_A = 25 °C, unless otherwise specified

 ${}^{1}G_{\mathsf{ma}} = |S_{21\mathrm{e}} / S_{12\mathrm{e}}| \; (\mathrm{k} \cdot (\mathrm{k}^{2} \cdot 1)^{1/2}), \; G_{\mathsf{ms}} = |S_{21\mathrm{e}} / S_{12\mathrm{e}}|$

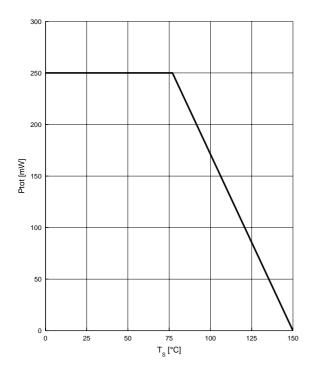
²IP3 value depends on termination of all intermodulation frequency components.

Termination used for this measurement is 50Ω from 0.1 MHz to 6 GHz



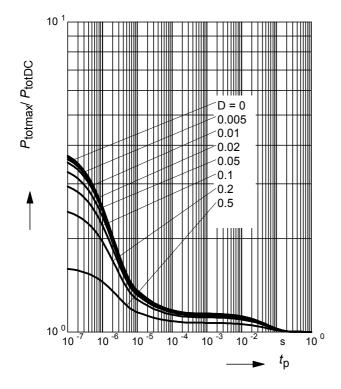
Total power dissipation $P_{tot} = f(T_S)$

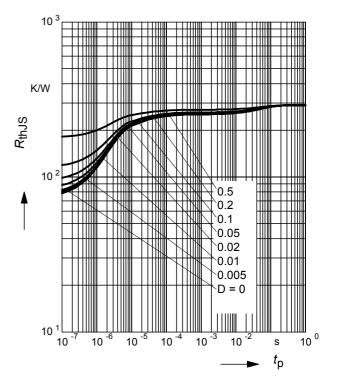
Permissible Pulse Load $R_{\text{thJS}} = f(t_p)$



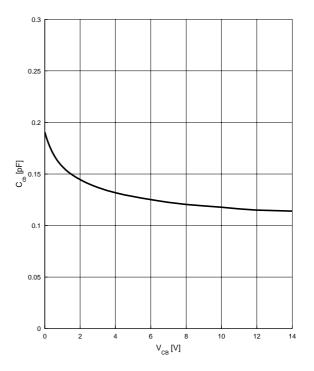
Permissible Pulse Load

 $P_{\text{totmax}}/P_{\text{totDC}} = f(t_p)$





Collector-base capacitance $C_{cb} = f (V_{CB})$ f = 1 MHz



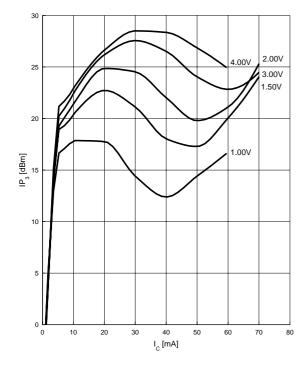
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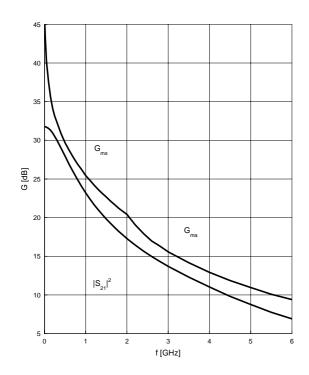
Third order Intercept Point $IP_3 = f(I_C)$

(Output, $Z_{\rm S}$ = $Z_{\rm L}$ = 50 Ω)

 V_{CE} = parameter, f = 900 MHz

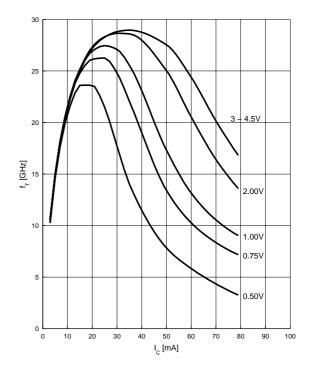


Power gain G_{ma} , $G_{ms} = f(f)$ $V_{CE} = 3 \text{ V}$, $I_C = 25 \text{ mA}$

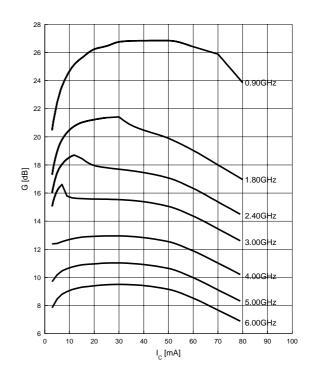


Transition frequency $f_{\rm T} = f(I_{\rm C})$

 V_{CE} = parameter in V, f = 2 GHz



Power gain G_{ma} , $G_{ms} = f(I_C)$ $V_{CE} = 3 V$ f = parameter in GHz

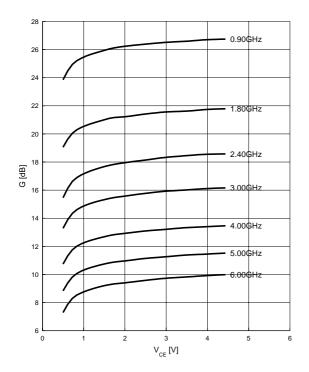


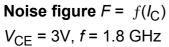


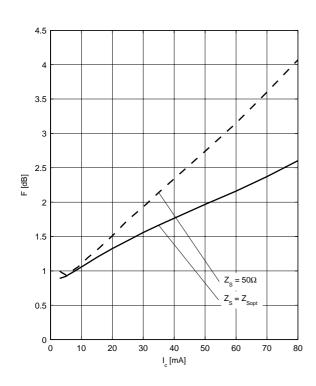
Power gain G_{ma} , $G_{ms} = f(V_{CE})$

*I*_C = 20 mA

f = parameter in GHz



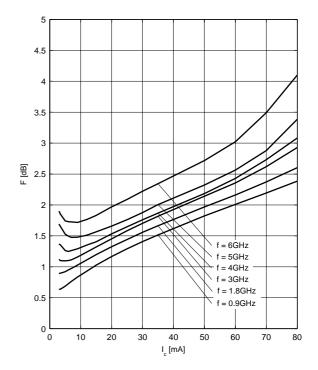




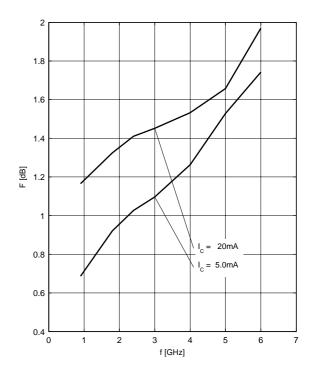
Noise figure $F = f(I_C)$

 V_{CE} = 3 V, f = parameter in GHz

 $Z_{\rm S} = Z_{\rm Sopt}$



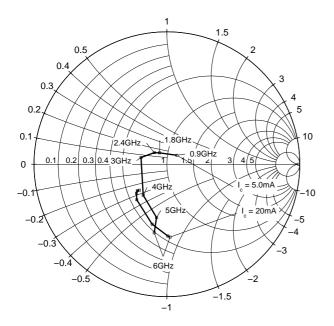
Noise figure F = f(f) $V_{CE} = 3 V, Z_S = Z_{Sopt}$



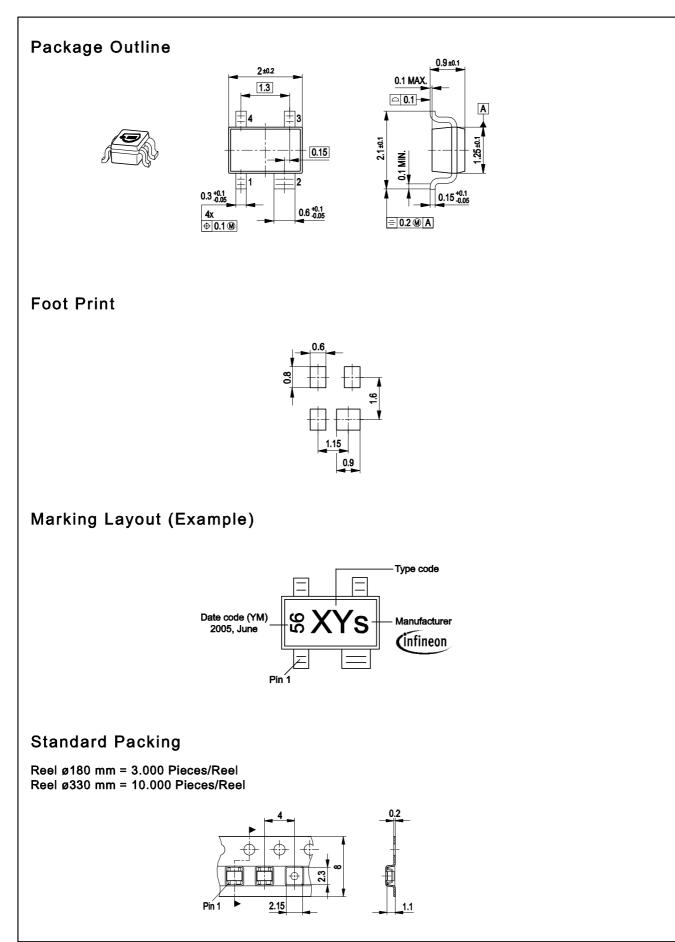




Source impedance for min. noise figure vs. frequency V_{CE} = 3 V, I_{C} = 5 mA / 20 mA









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